

Perfect invisibility concentrator with simplified material parameters

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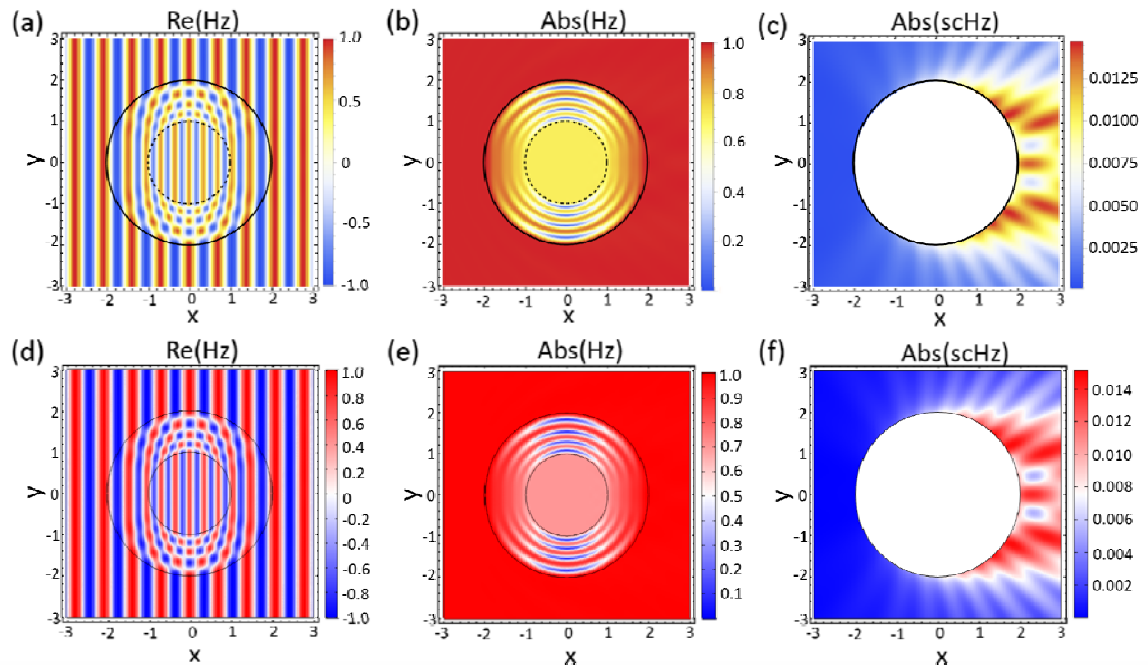


Fig. S1 Fields of concentrator in Case A. Analytical calculation: **(a)** Real part of magnetic field. **(b)** Absolute value of magnetic field. **(c)** Absolute value of scattering magnetic field. Numerical simulation: **(d)** Real part of magnetic field. **(e)** Absolute value of magnetic field. **(f)** Absolute value of scattering magnetic field.

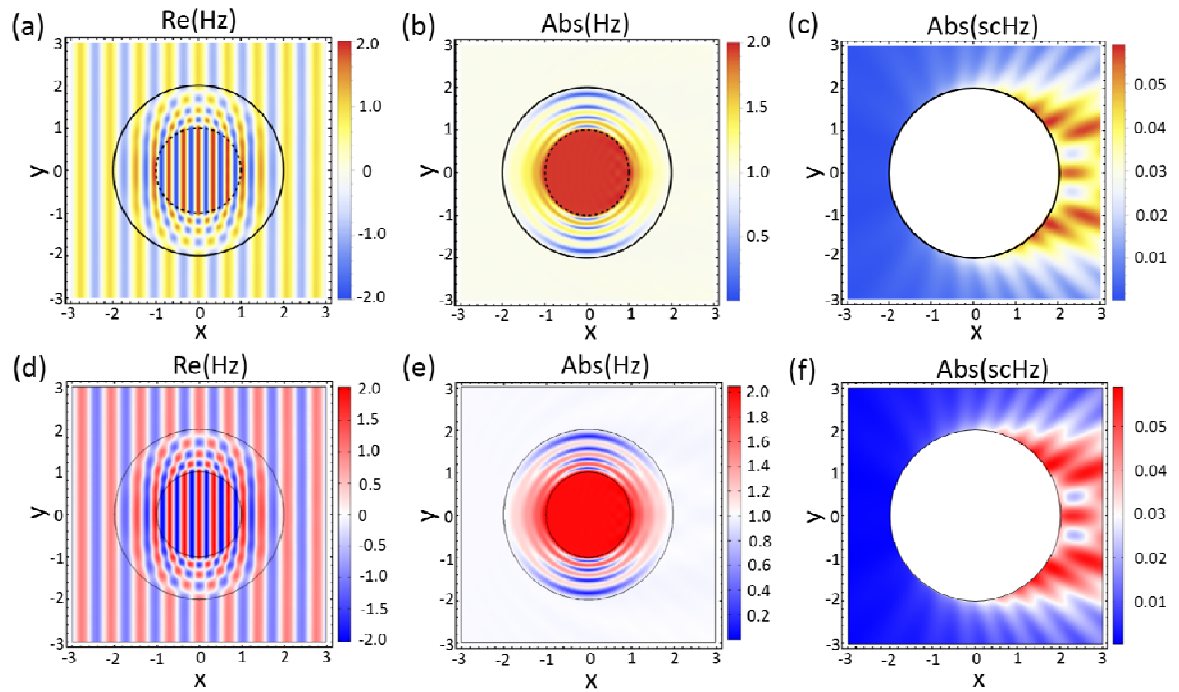


Fig. S2 Fields of concentrator in Case B. Analytical calculation: **(a)** Real part of magnetic field. **(b)** Absolute value of magnetic field. **(c)** Absolute value of scattering magnetic field. Numerical simulation: **(d)** Real part of magnetic field. **(e)** Absolute value of magnetic field. **(f)** Absolute value of scattering magnetic field.
